

Notice of References Cited	Application/Control No. 10/802,184		Applicant(s)/Patent Under Reexamination YOSHII ET AL.	
	Examiner James A. Dudek		Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,522,377	02-2003	Kim et al.	349/114
*	C	US-6,917,393	07-2005	Sakamoto et al.	349/43
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NON-PATENT DOCUMENTS

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